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# Direct Nanoparticle Printing of CL-20 Using Ultrafast Laser Irradiation

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Sandia National Laboratories



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# Abstract

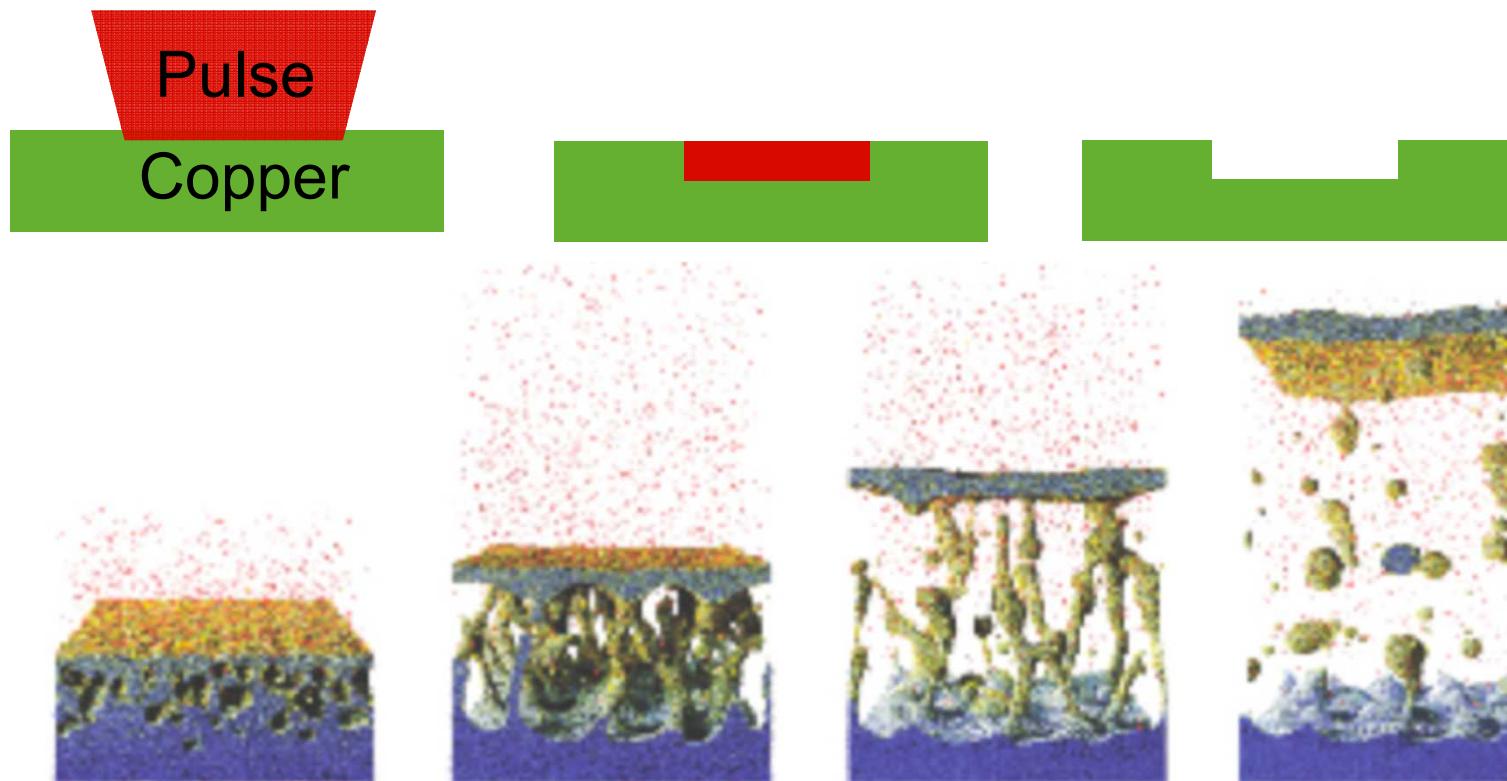
We have applied a nanoparticle laser-printing technique to energetic materials using CL-20 film lift-off from glass substrates after ultrafast ( $\sim 50$  fs pulse length) irradiation in air. Unique interactions of ultrafast laser pulses with the thin film energetic material allow for the deposition of micron-scale and nanoparticles onto glass substrates. Control over printed particles, such as the printed distribution, is achieved by changing the laser fluence and film-substrate distance. We demonstrate  $2.8\text{ }\mu\text{m}$  CL-20 film removal from substrates resulting in rapid particle printing in air. Particles are printed and then characterized using optical and electron microscopy. Future work will also be discussed.

# Outline

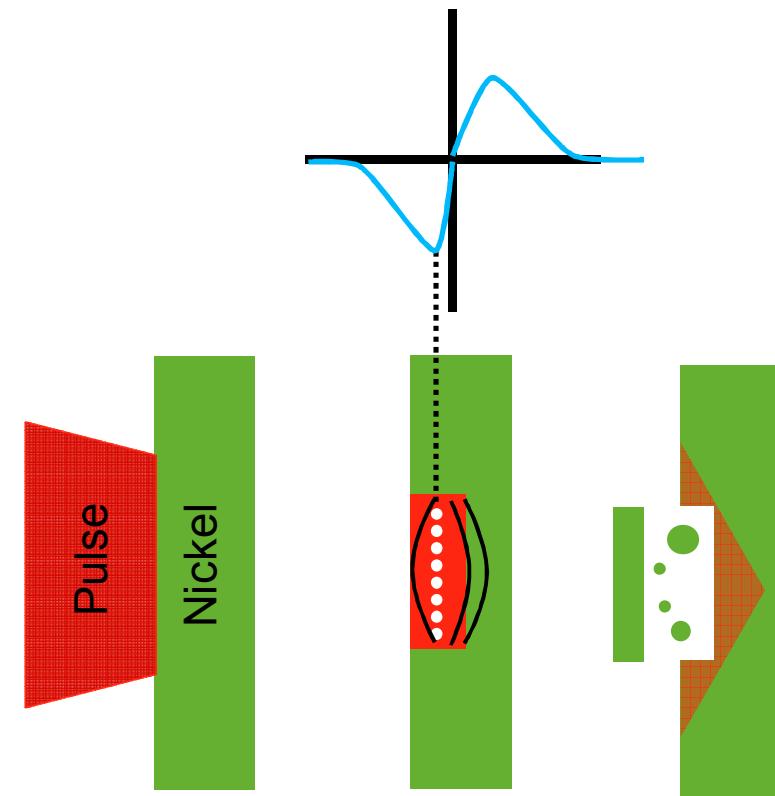
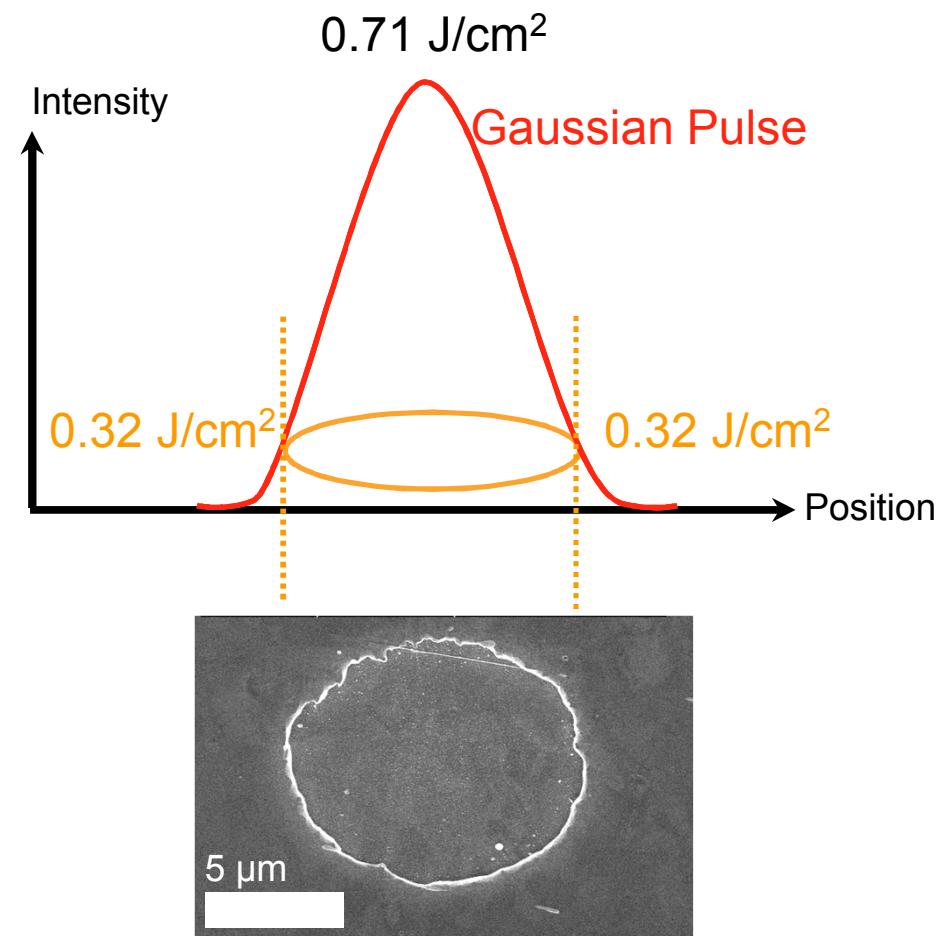
- Background work performed by Ryan Murphy
- Current Setup in the Explosives Component Facility
- Experimental Setup
- Results
- Future Work

# Ultrafast Laser Damage in Bulk Materials

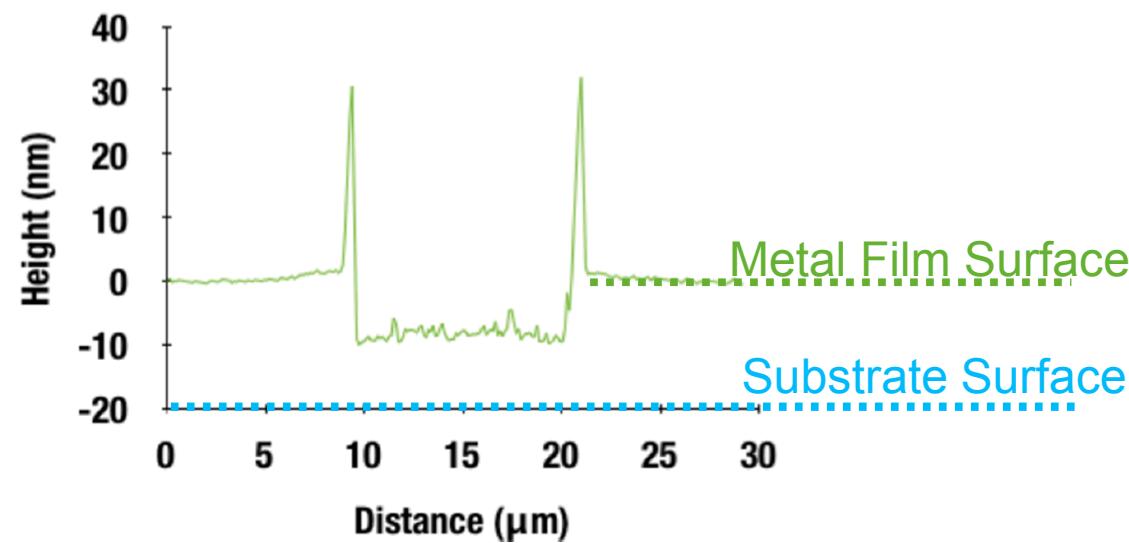
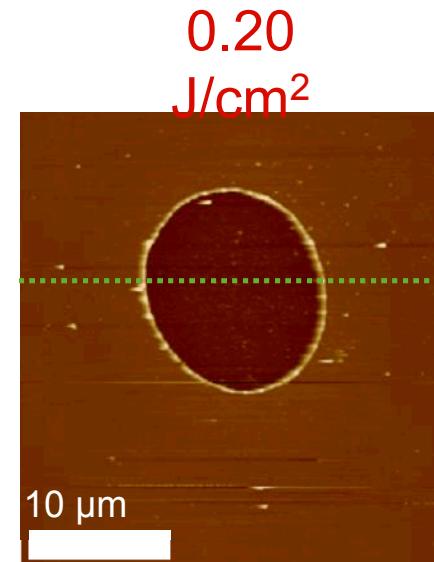
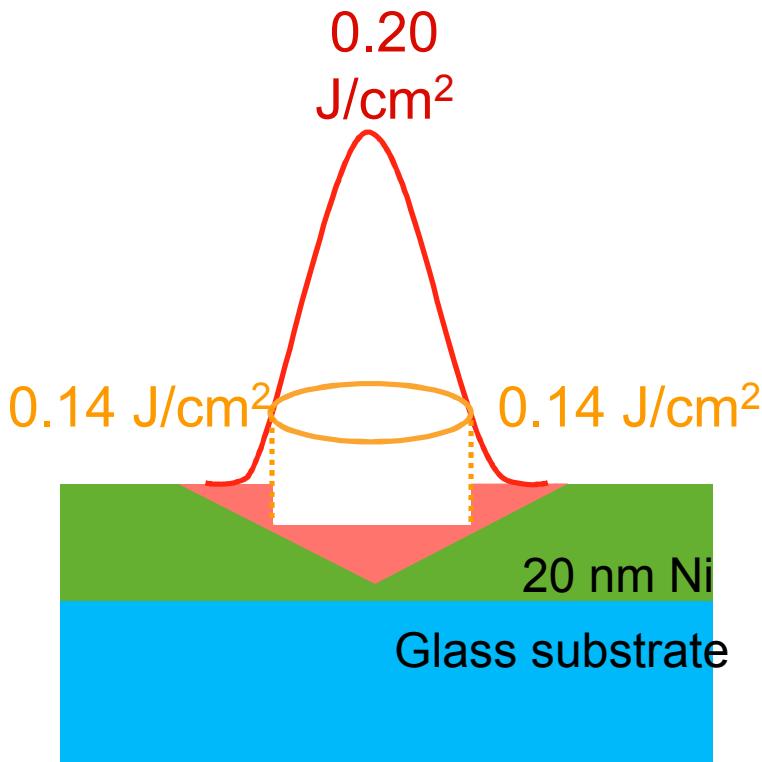
- First few nanometers of material melts in  $\sim 3$  ps.
- Rapid expansion leads to homogeneous void nucleation within melt.
- Material “breaks” where voids nucleate.



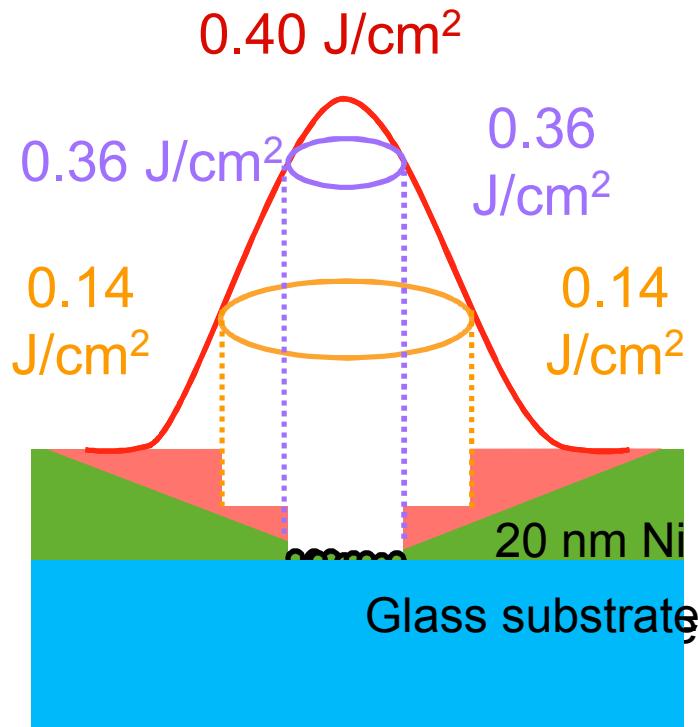
# Deterministic Thresholds



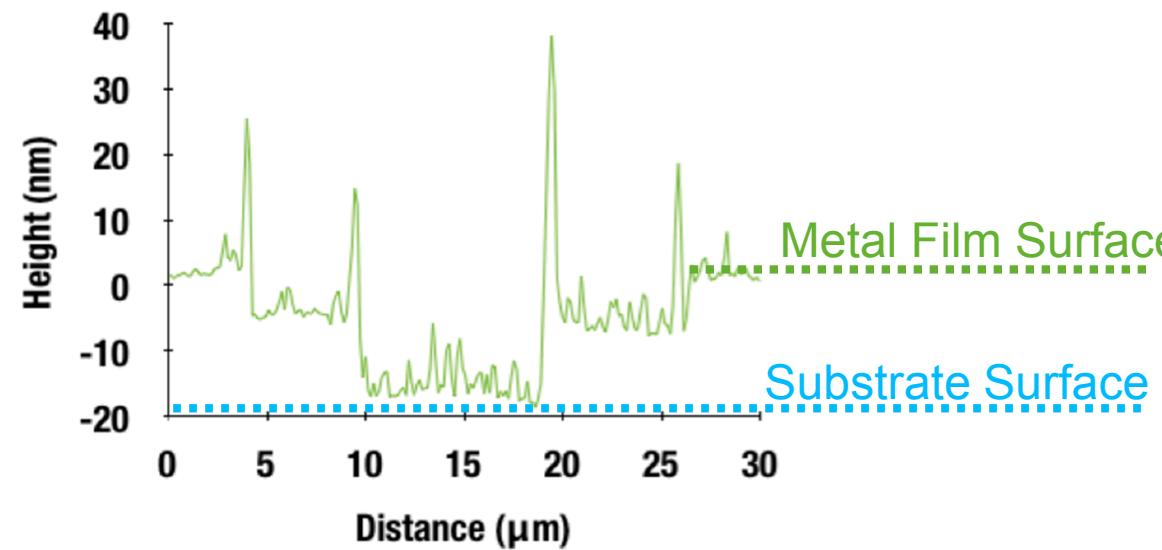
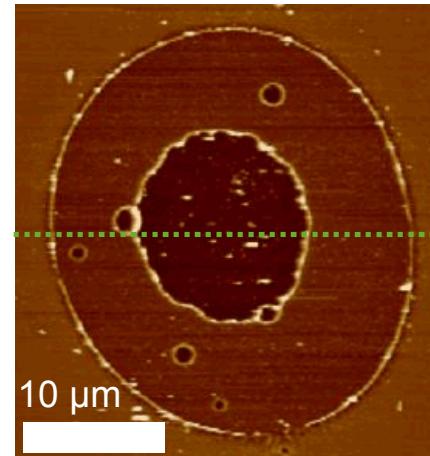
# Low Fluence Removal Within Film



# High Fluence Removal Within Film + at Interface

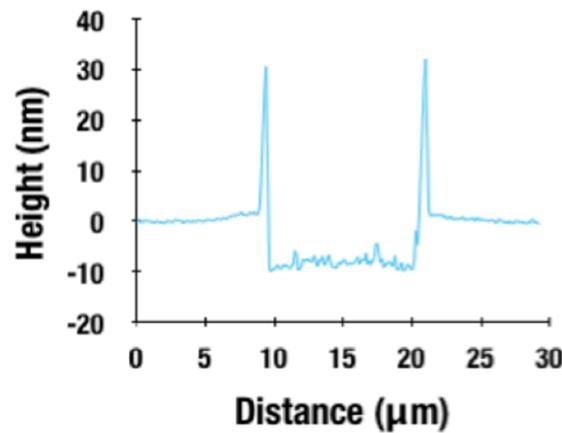
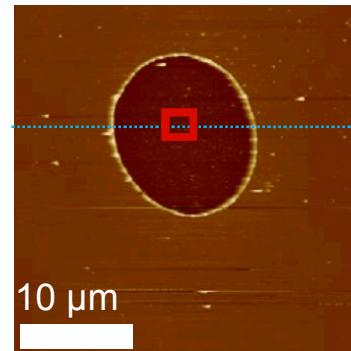


0.40 J/cm<sup>2</sup>

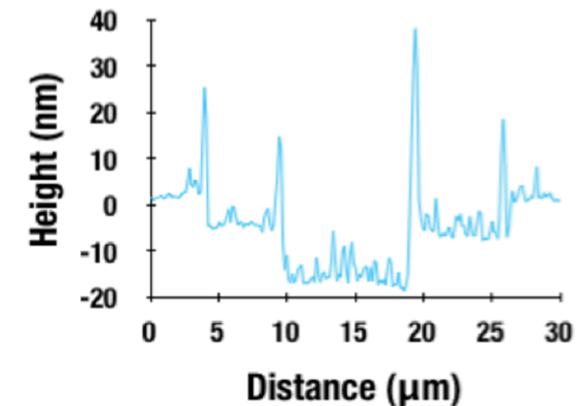
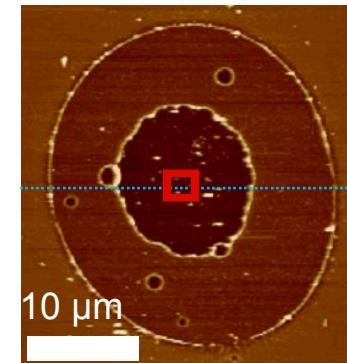


# Void Nucleation Controls Surface Roughness

0.20 J/cm<sup>2</sup>

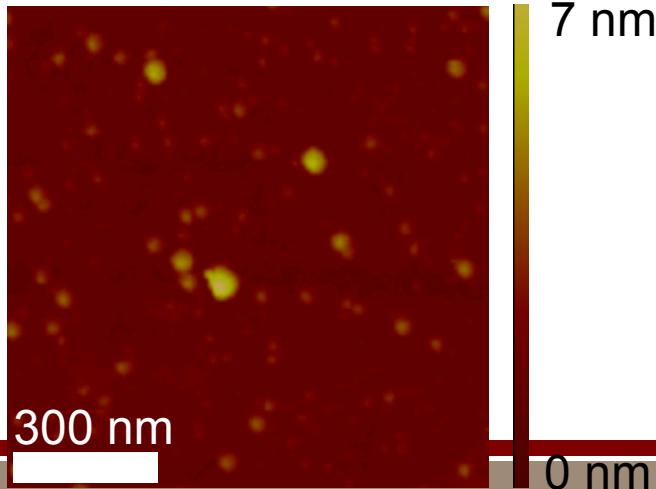


0.40 J/cm<sup>2</sup>



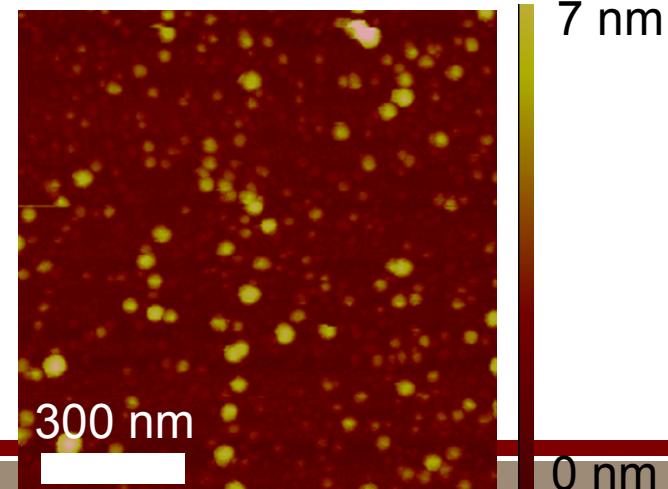
## Intra-film Separation

RMS Roughness = 1.27 nm

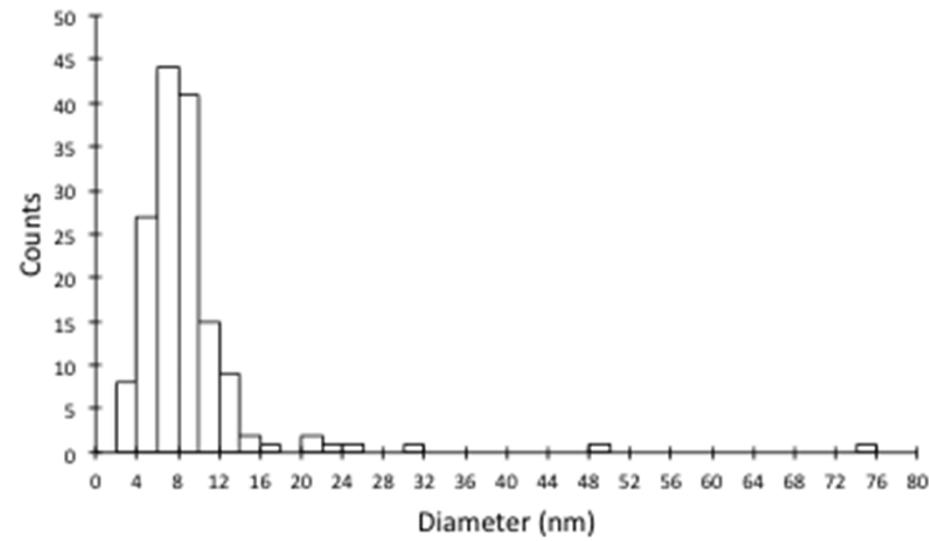
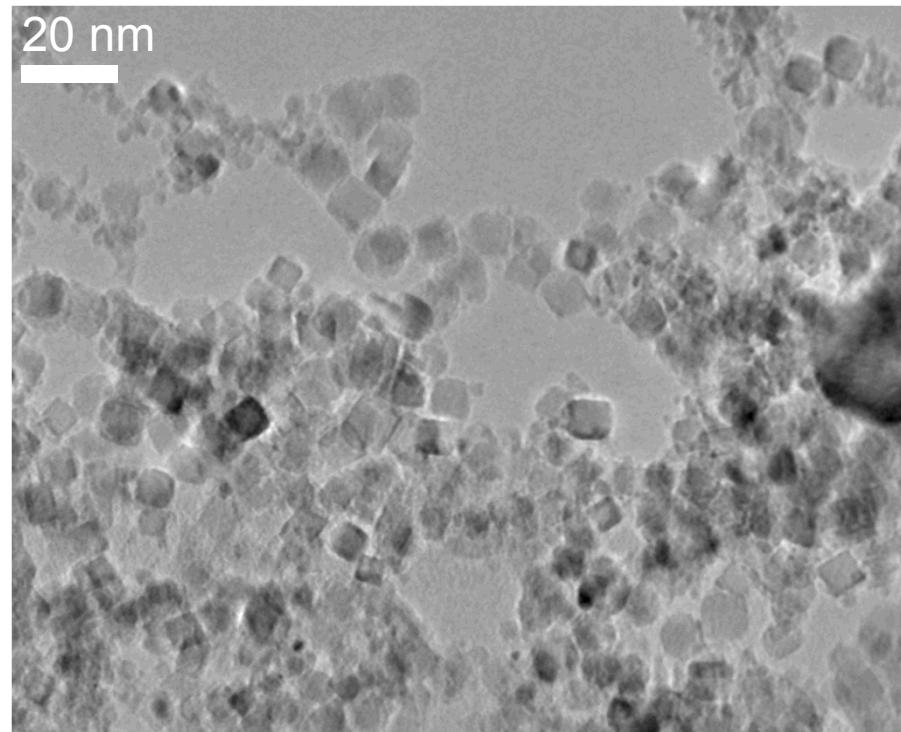
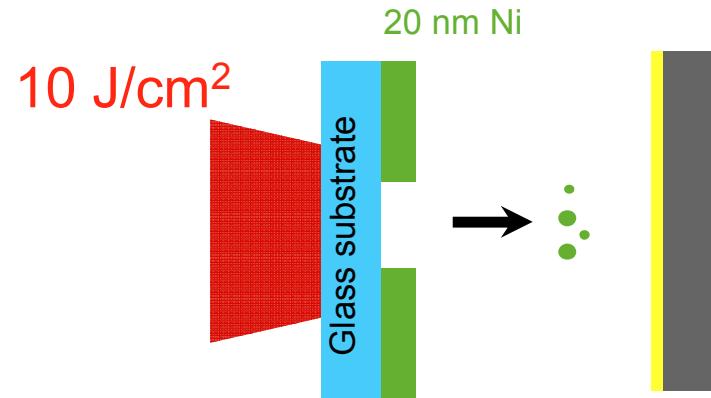


## Interface Separation

RMS Roughness = 3.06 nm



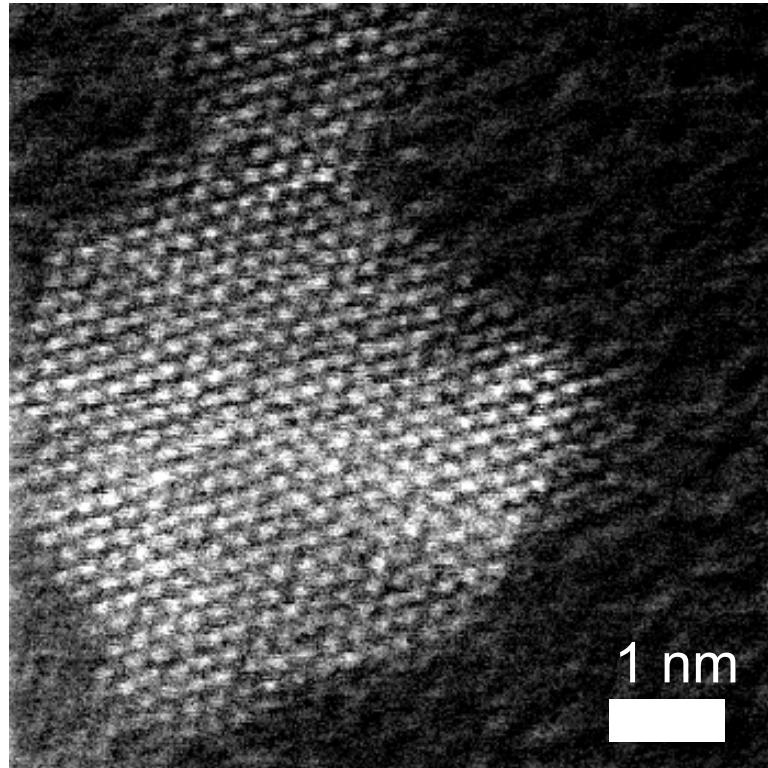
# Ni Nanoparticle Printing



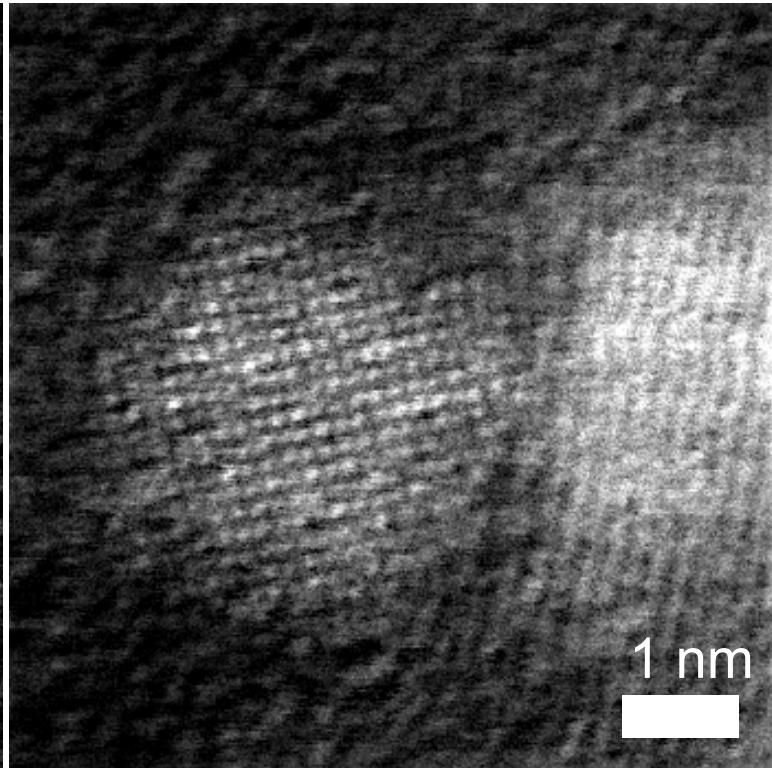
- Can we pattern surfaces with energetic materials using laser ablation?

# Faceted Nanoparticles

*Atomic Resolution*

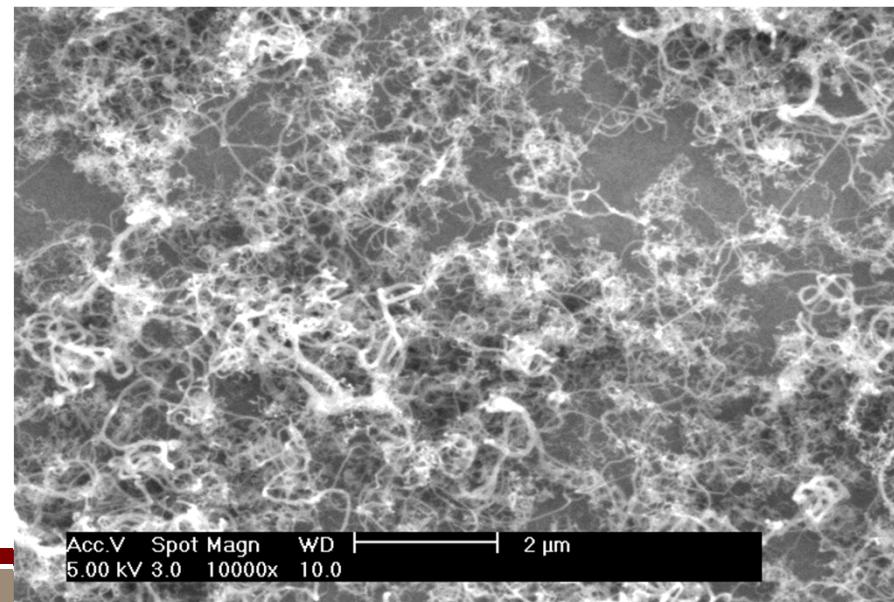
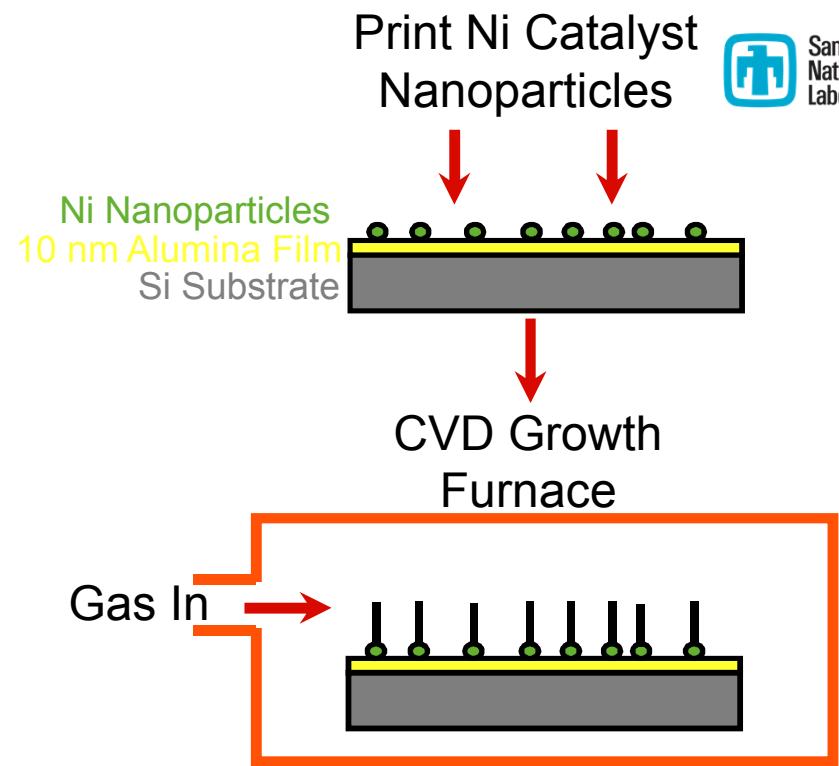
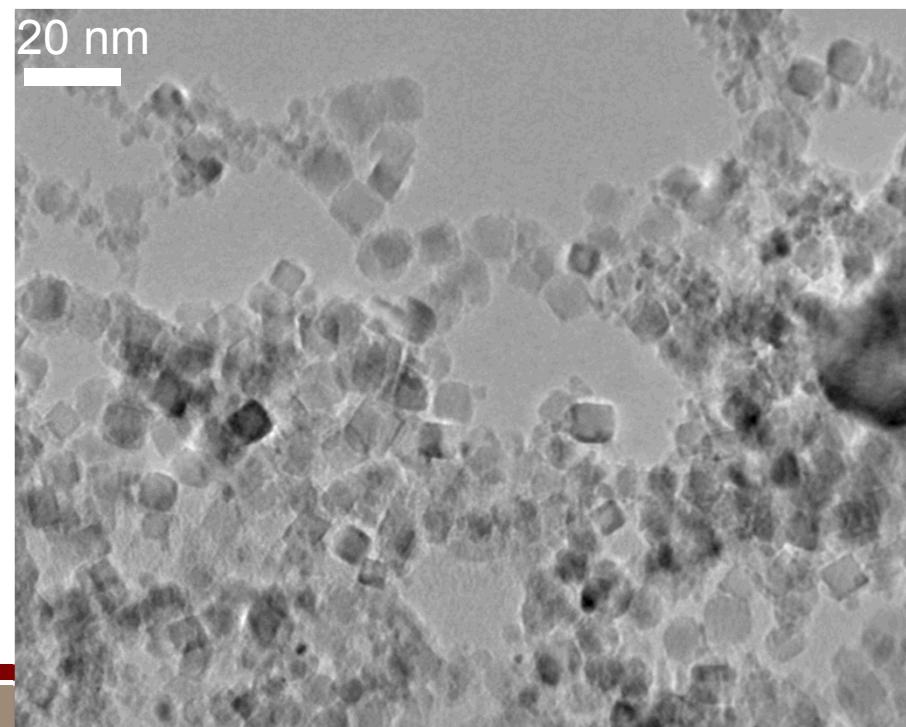
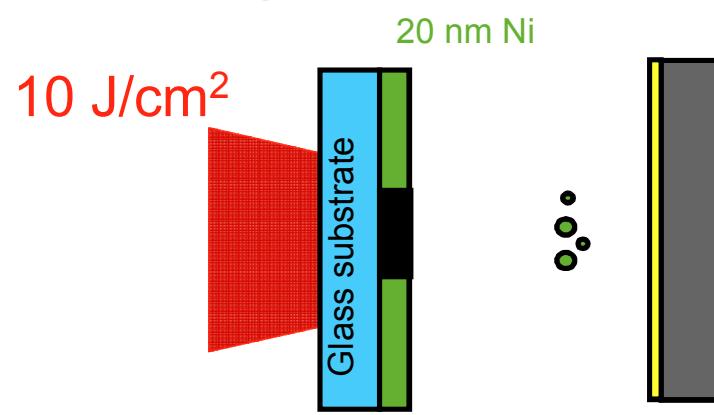


1 nm

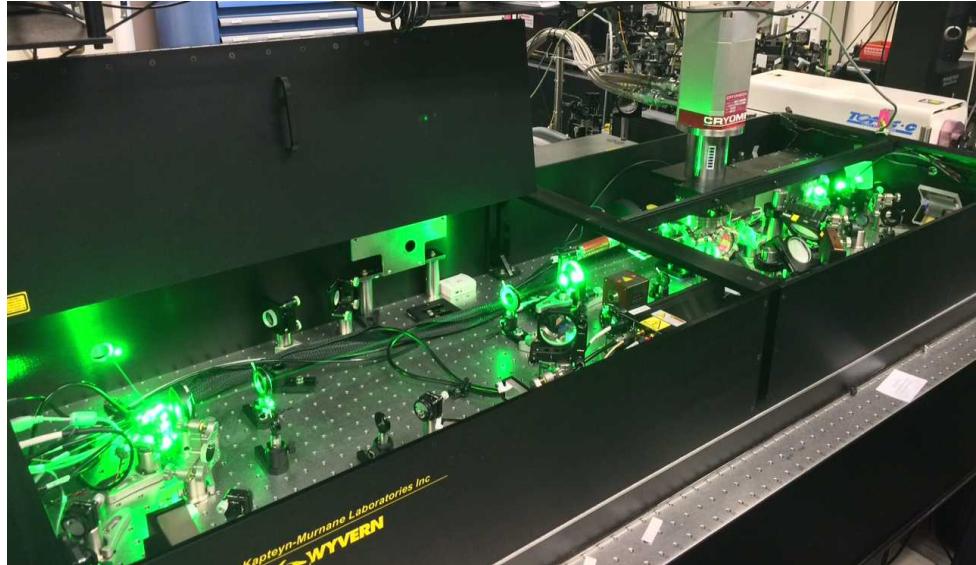
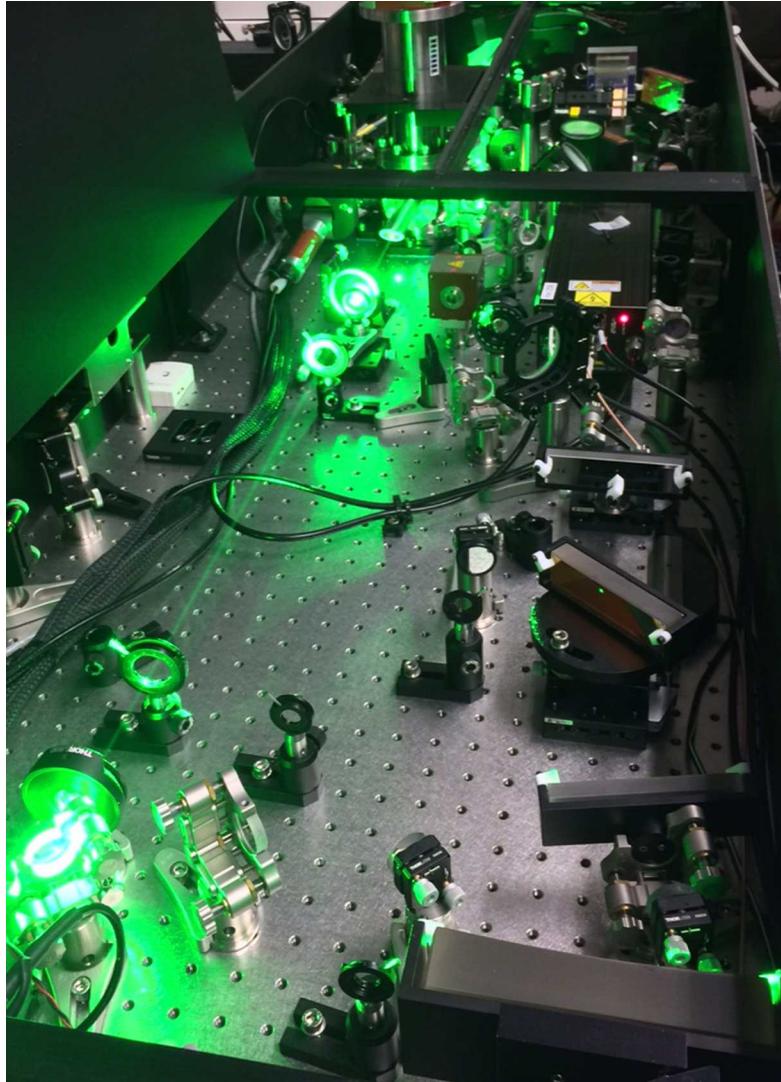


1 nm

# Ni Nanoparticle Printing



# Laser Setup ECF



## Laser Parameters

4 mJ

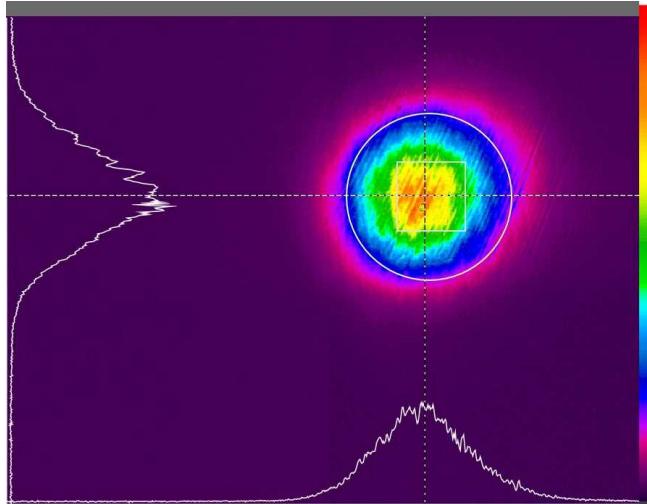
1 kHz (Single shot capable)

40 fs pulse width

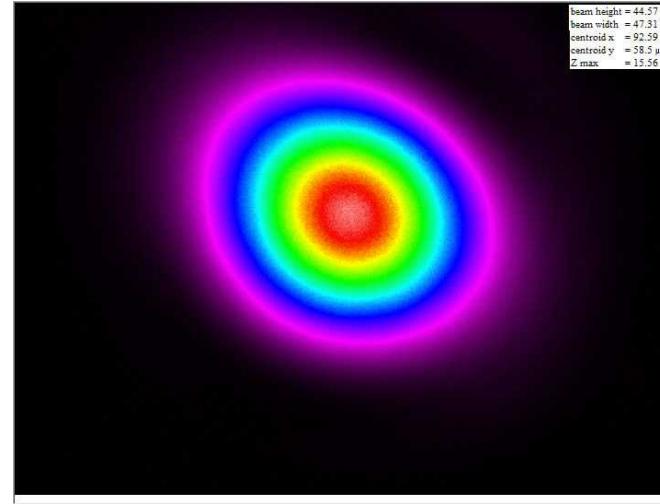
35 nm bandwidth

785 nm center wavelength

# Laser Setup Diagnostics



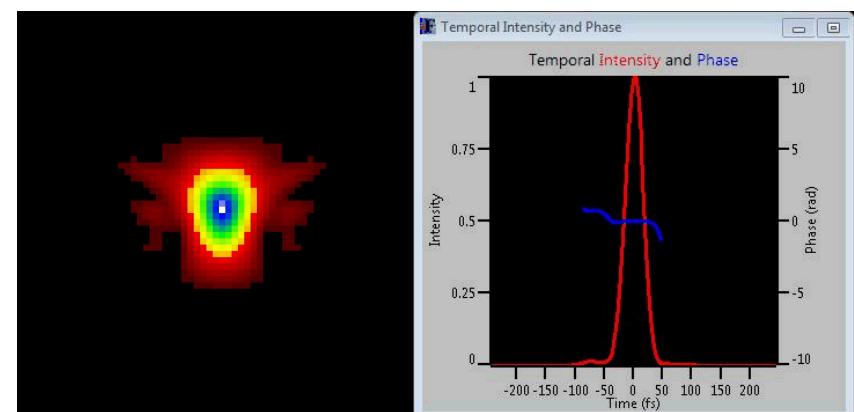
Nearfield Camera



Farfield Camera

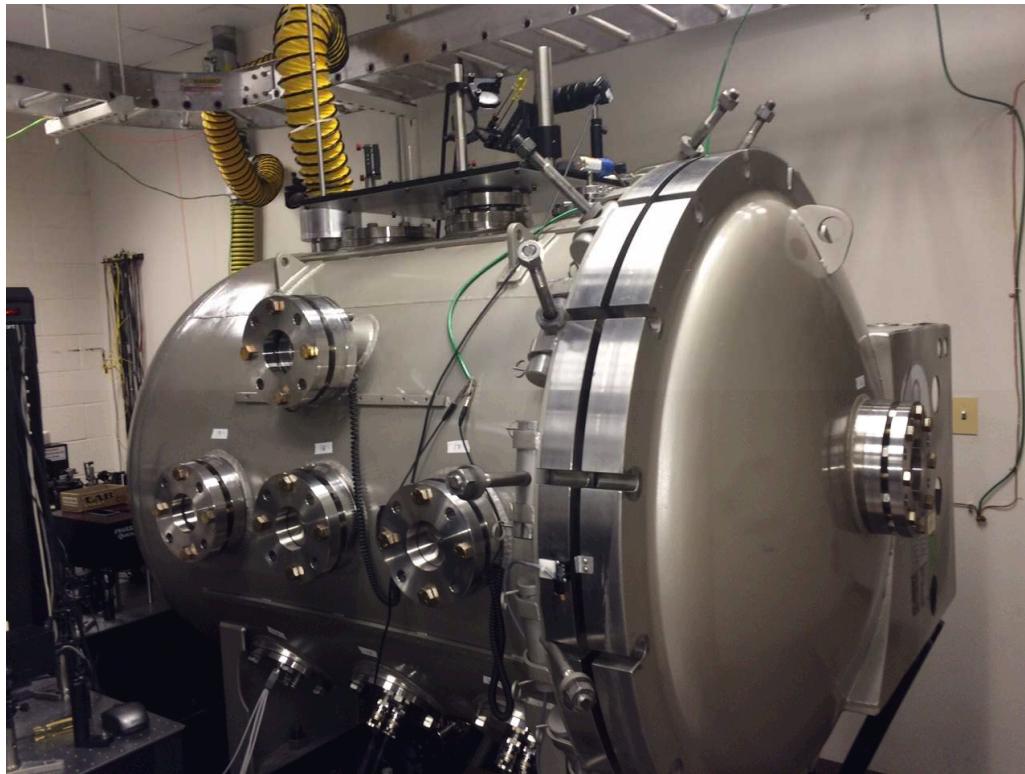


Spectrometer

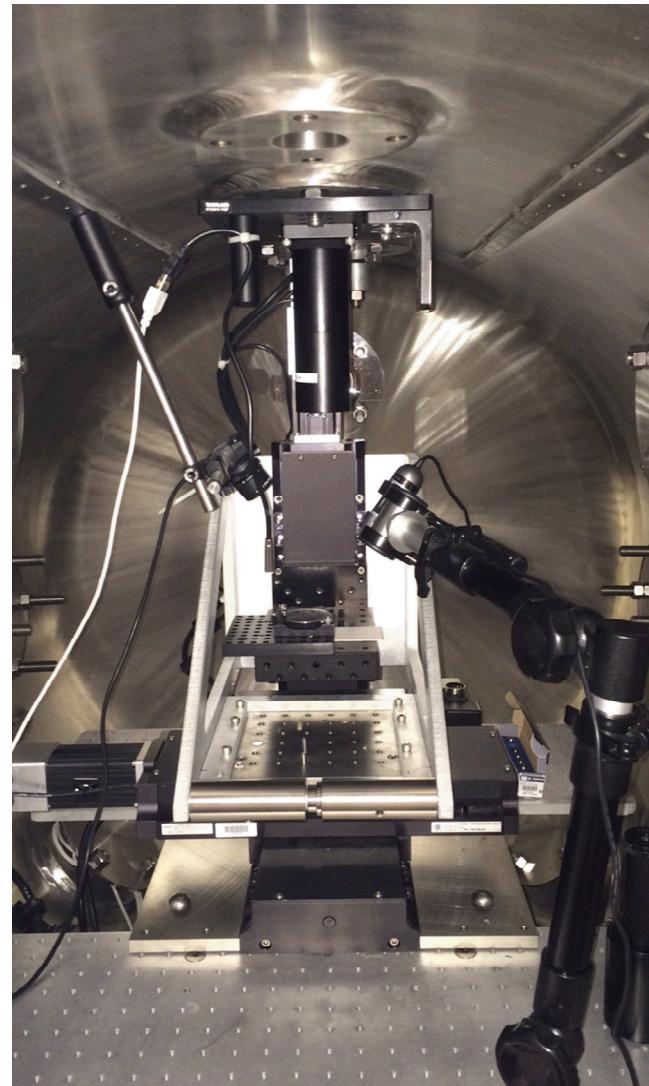


FROG

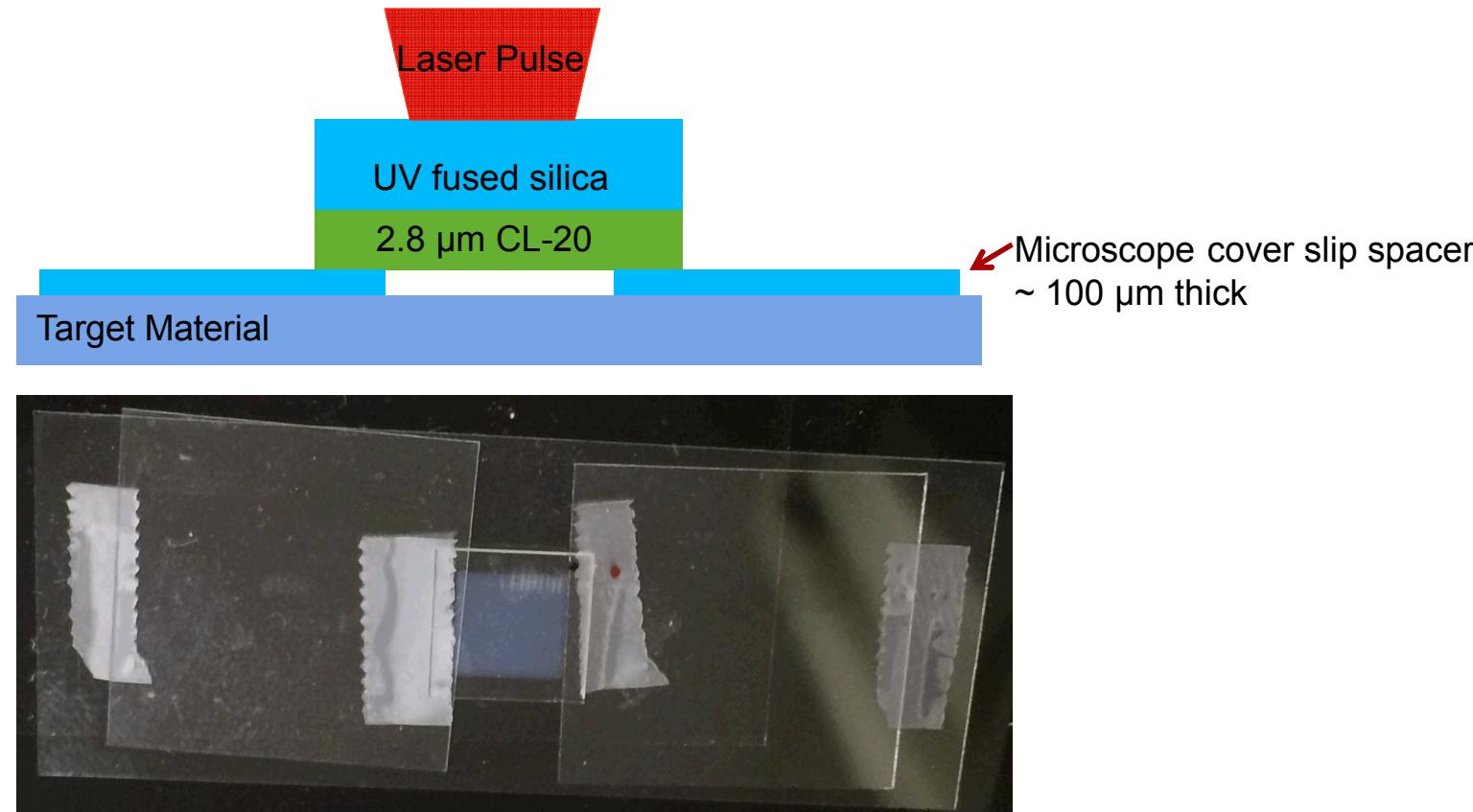
# Experimental Setup



Explosives chamber  
10g TNT equivalent capacity  
Vacuum chamber and full venting  
Aerotech 3-D computer controlled  
stage  
3 cameras for remote viewing



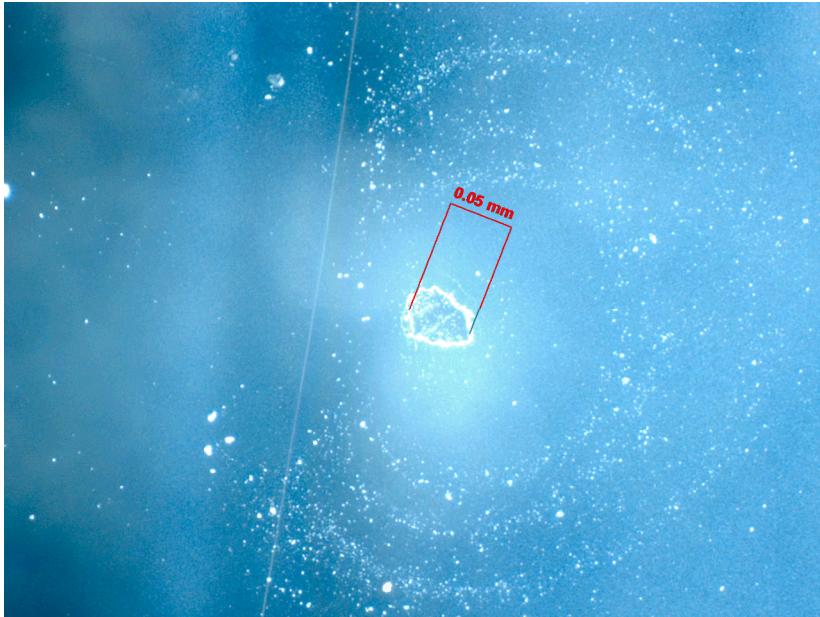
# Experimental Setup- Samples



# Data Set

- Thin film CL-20 sample (2.8  $\mu\text{m}$ )
- Focusing optic – 200 mm fl lens ( $\sim 20\mu\text{m}$  spot size)
- Spacer distance  $\sim 100 \mu\text{m}$  cover slip spacer
- Pulse width  $\sim 40 \text{ fs}$  –close to transform limited
- Five energy levels
  - 160  $\mu\text{J}$  (damaged the target), 80  $\mu\text{J}$ , 40 $\mu\text{J}$ , 20  $\mu\text{J}$ , 15 $\mu\text{J}$  (ablation threshold)

# Results 80 uJ – Optical Microscope

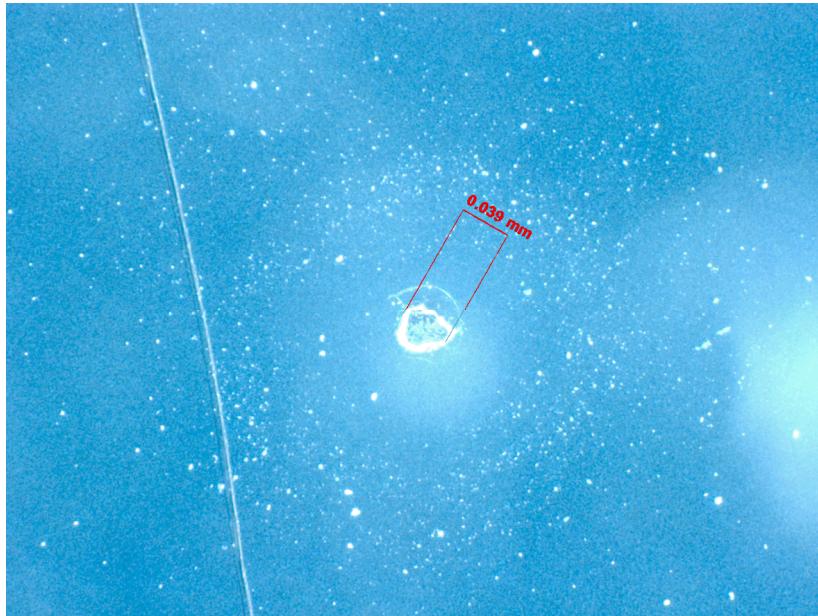


Laser spot profile on CL-20 film  
50  $\mu\text{m}$  film spot

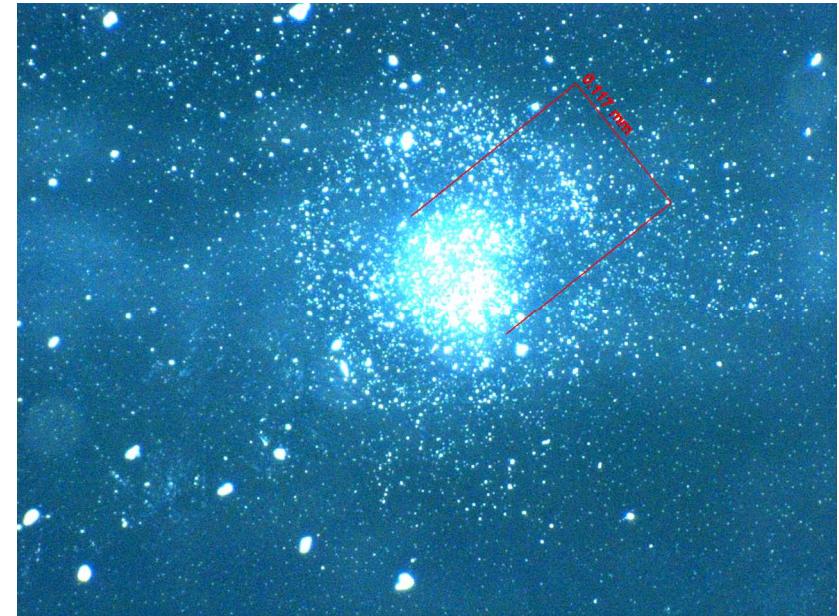


Printed CL-20 particles  
~100  $\mu\text{m}$  particle distribution

# Results 40 uJ – Optical Microscope

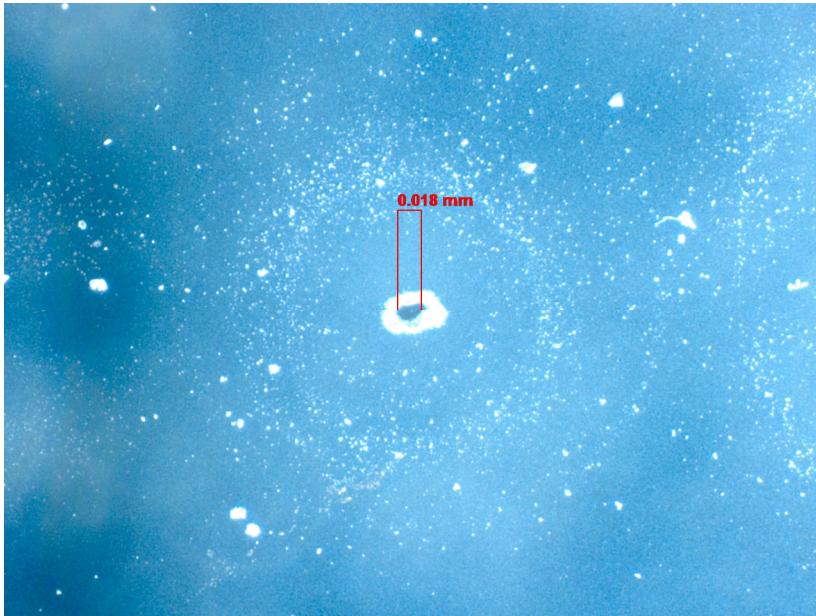


Laser spot profile on CL-20 film  
40  $\mu\text{m}$  film spot



Printed CL-20 particles  
~100  $\mu\text{m}$  particle distribution

# Results 20 uJ – Optical Microscope

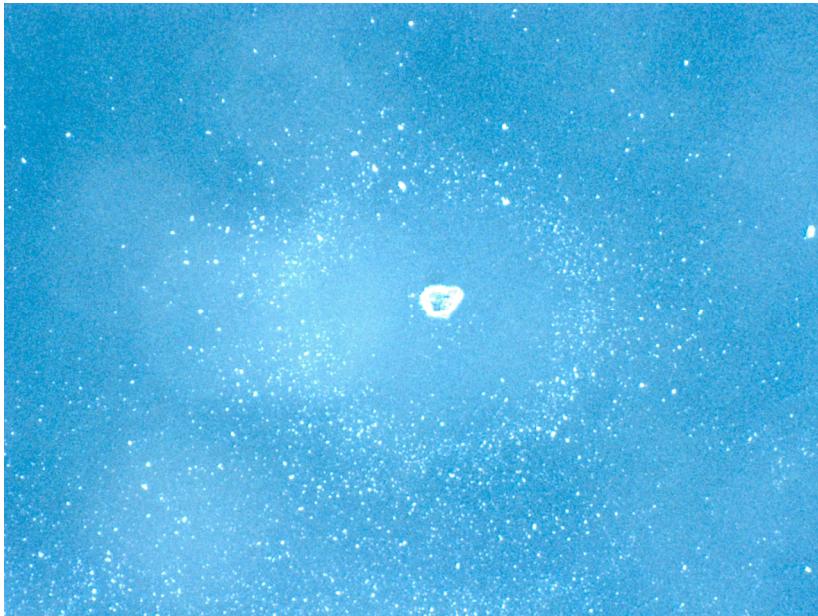


Laser spot profile on CL-20 film  
18  $\mu\text{m}$  film spot



Printed CL-20 particles  
~70  $\mu\text{m}$  particle distribution

# Results 15 uJ – Optical Microscope

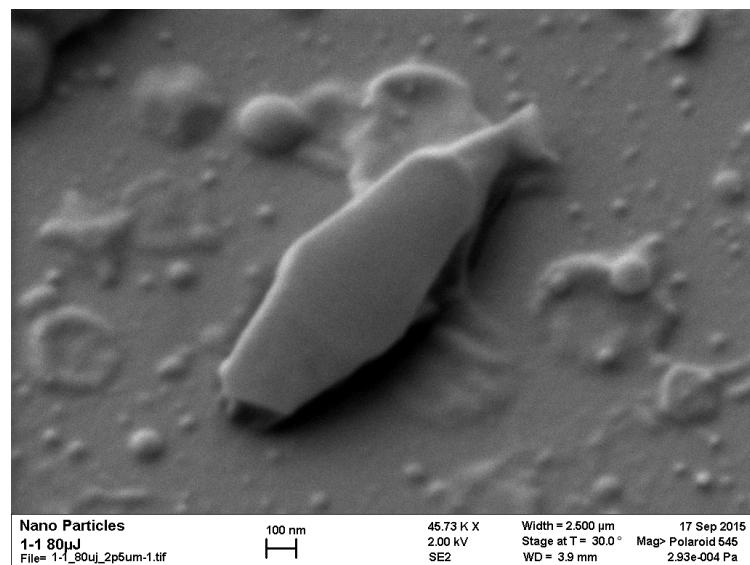
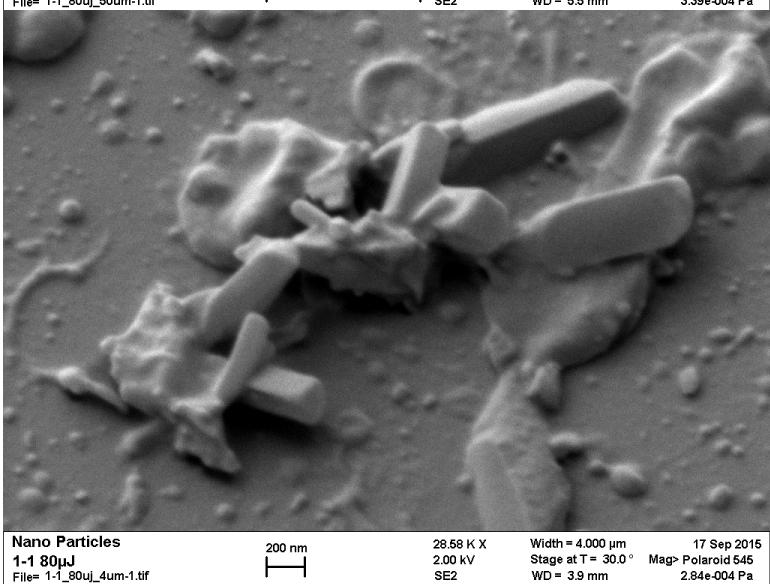
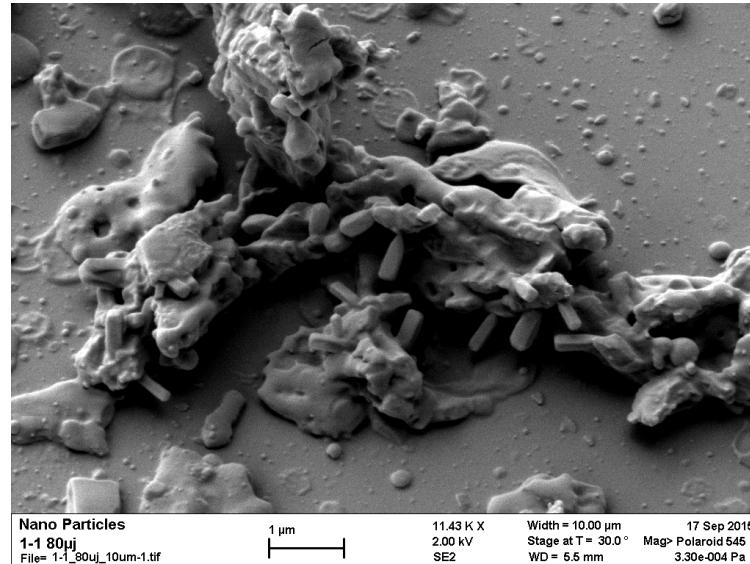
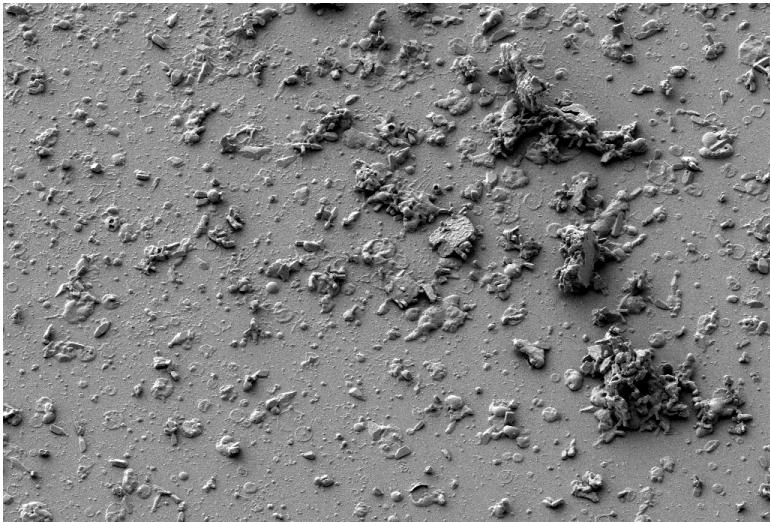


Laser spot profile on CL-20 film  
17  $\mu\text{m}$  film spot size

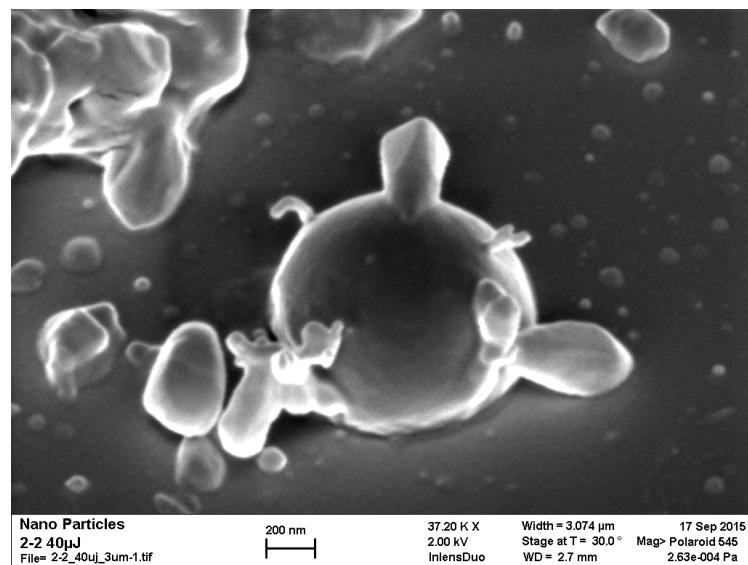
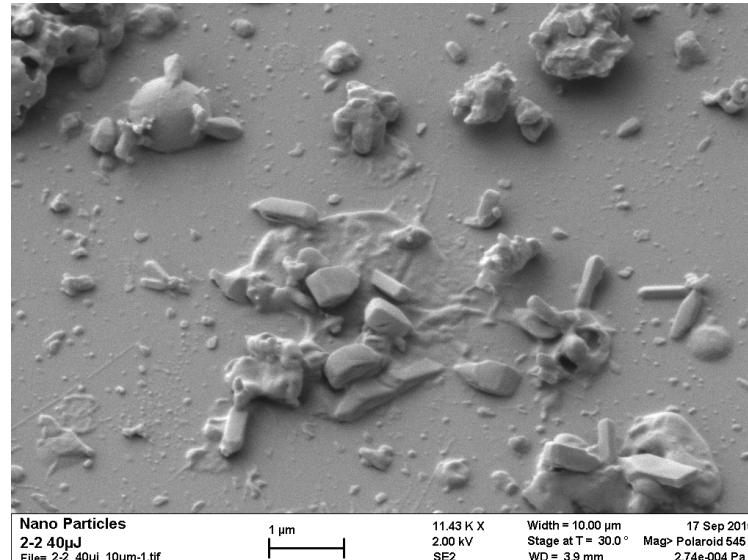
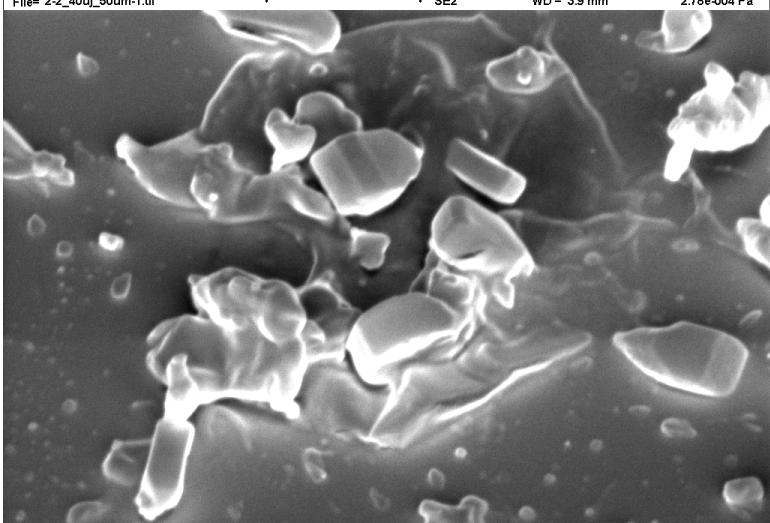
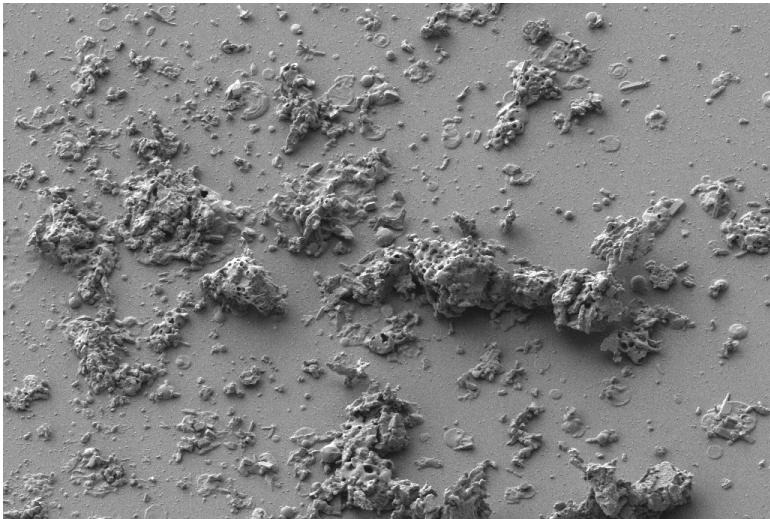


Printed CL-20 particles  
~70  $\mu\text{m}$  particle distribution

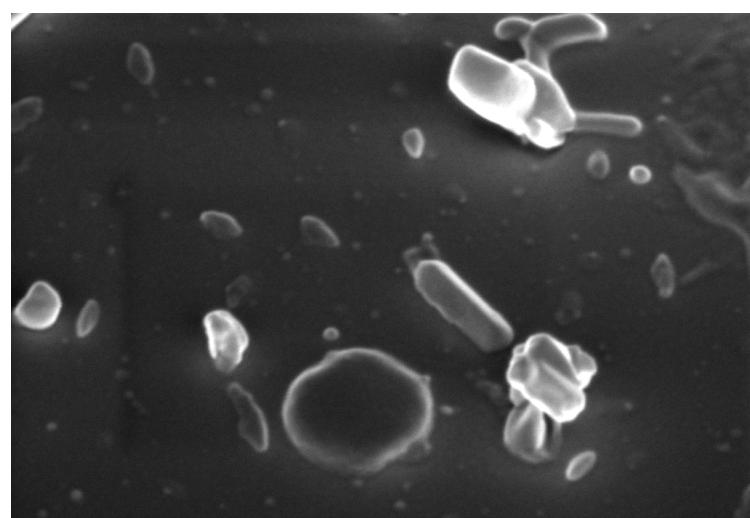
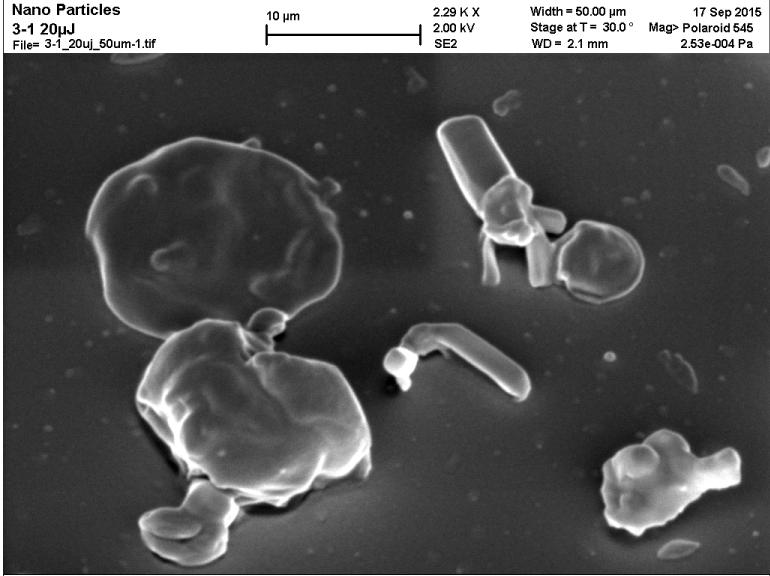
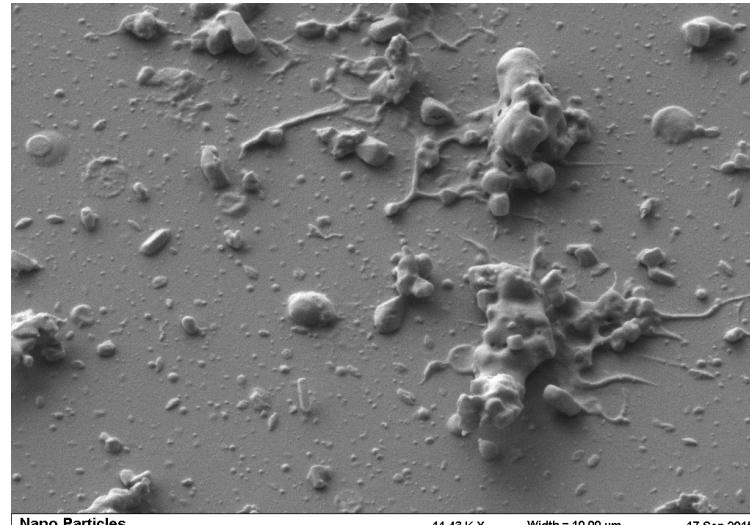
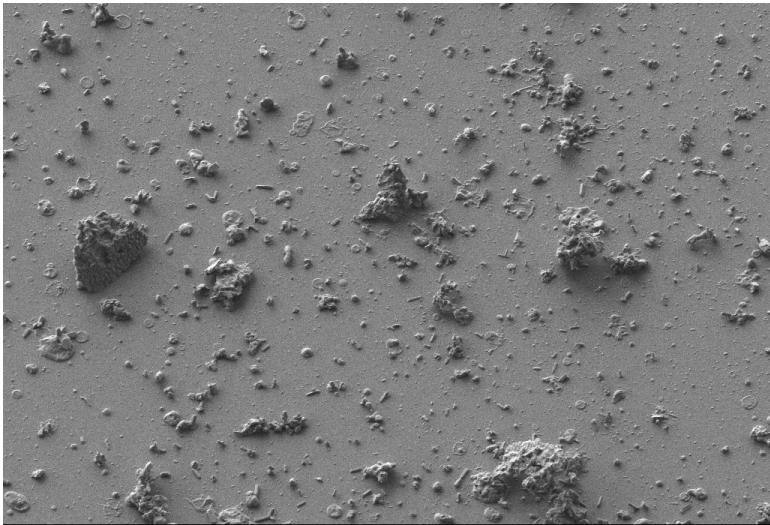
# Results 80 uJ – SEM



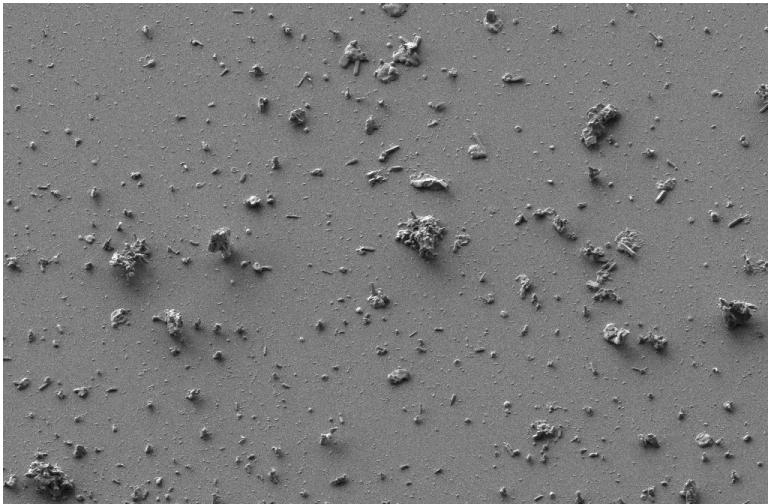
# Results 40 uJ – SEM



# Results 20 uJ – SEM

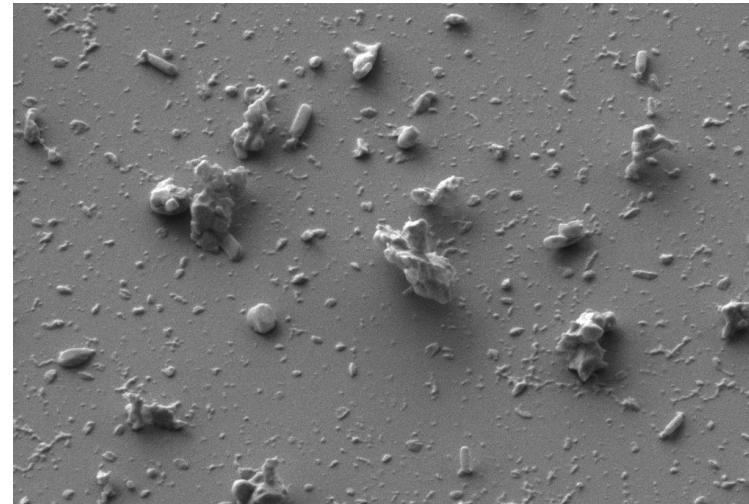


# Results 15 uJ – SEM



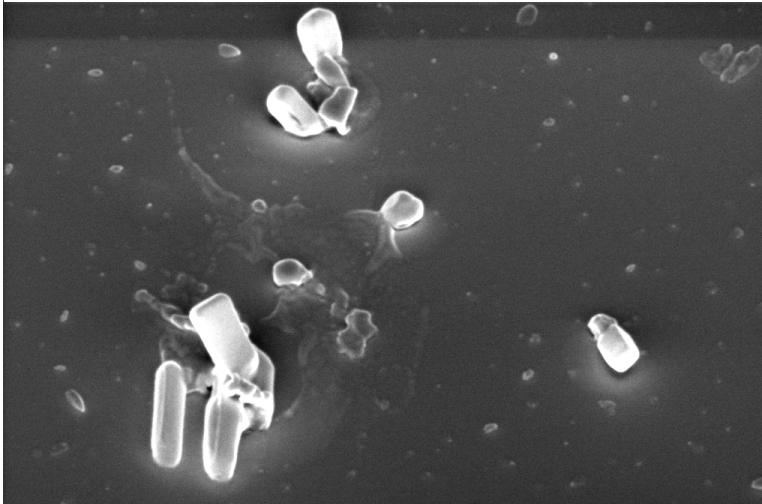
**Nano Particles**  
4-1 15μJ  
File= 4-1\_15uj\_50um-1.tif

10 μm 2.29 K X 2.00 kV SE2  
Width = 50.00 μm Stage at T = 30.0° Mag> Polaroid 545  
WD = 2.1 mm 2.40e-004 Pa



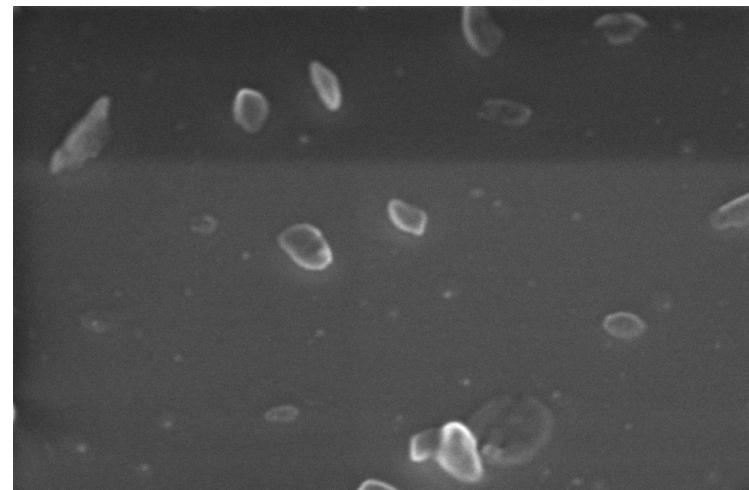
**Nano Particles**  
4-1 15μJ  
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1 μm 11.43 K X 2.00 kV SE2  
Width = 10.000 μm Stage at T = 30.0° Mag> Polaroid 545  
WD = 2.1 mm 2.37e-004 Pa



**Nano Particles**  
4-1 15μJ  
File= 4-1\_15uj\_5um-1.tif

1 μm 22.87 K X 2.00 kV InlensDuo  
Width = 5.000 μm Stage at T = 30.0° Mag> Polaroid 545  
WD = 2.1 mm 2.31e-004 Pa



**Nano Particles**  
4-1 15μJ  
File= 4-1\_15uj\_2-5um-1.tif

200 nm 45.73 K X 2.00 kV InlensDuo  
Width = 2.500 μm Stage at T = 30.0° Mag> Polaroid 545  
WD = 2.1 mm 2.33e-004 Pa

# Results- Discussion

- Too high energy damages the target material
- High fluence appears to give larger particle agglomeration
- Generating particles close to the ablation threshold appears to give a more uniform particle size distribution

# Future Work

- Changing film thickness has shown with other materials to influence nanoparticle size. We would like to investigate using multiple film thickness samples
- Stand off and focusing geometry both contribute to the macro deposited spot. Would like to investigate different geometries.
  - As part of this we would like to pursue printing different features including continuous lines
- All work was done at a fixed pulse width  $\sim$ 40 fs. Would like to investigate chirping the pulse
- All work was done at 785 nm. Other work shows more efficient ablation closer to the UV. Could frequency double the light.

# Future Work - Cont

- Analysis was limited to optical microscope and SEM. We plan on doing TEM measurements to validate that no changes were made to the energetic material. X-ray diffraction measurements are also a possibility.